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Dr. Anderson works in system measurement and evaluation at the Thomas J. Watson Research Center. He has been with IBM since 1965, specializing in computer-aided design of integrated circuits and computer performance evaluation. His education includes a B.S. in mathematics, University of Rhode Island, 1961; an M.S. in physics, Trinity College, 1965; and a Ph.D. in systems and information science, Syracuse University, 1972, where he was an IBM Resident Study Fellow. Prior to joining IBM, Dr. Anderson was a system analyst at the United Aircraft Research Laboratory, 1961 to 1964, and at Booz, Allen Applied Research, 1964 to 1965. He is a member of the Association for Computing Machinery.

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Dr. Bennett is in the theoretical physics group at the Thomas J. Watson Research Center. His current research is in two areas: molecular dynamics calculations of solid state diffusion and statistical mechanics of computers and self-organizing systems. From 1970 to 1972 he worked in the Solid State Science Division of Argonne National Laboratory on the molecular dynamics of freezing and the statistical mechanics of computation. His education includes an A.B. from Brandeis University in chemistry, 1964, and a Ph.D. from Harvard University in chemical physics, 1970.

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Dr. Dill is manager of the silicon process physics group at the Thomas J. Watson Research Center. He joined IBM in 1958 to work on exploratory semiconductor devices. His current interests are in semiconductor process technologies and their measurement. He received a B.S. degree in physics and M.S. and Ph.D. degrees in electrical engineering from the Carnegie Institute of Technology in 1954, 1956 and 1958, respectively. He is a senior member of the Institute of Electrical and Electronics Engineers.

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Dr. Flamholz is an advisory physicist in an advanced technology and analysis group at the Fishkill laboratory. He has been with IBM since 1968 and has worked in laser physics and applications, optical data processing, and currently in the development and analysis of laser and coherent optical techniques for application to product development and manufacturing. His education includes a B.S. from Brooklyn College in 1963, an M.S. in 1966, and a Ph.D. in applied physics in 1968, both from Cornell University. Dr. Flamholz is a member of the Optical Society of America and the American Physical Society. He has received an IBM outstanding contribution award for his work in optical data processing for mask inspection and measurement.

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Mr. Froot is a senior engineer in the technology assurance group of the Fishkill laboratory and is presently on assignment as the critical materials site representative. He has been with IBM since 1964. He has worked as a corrosion engineer at the International Nickel Company Research Laboratory from 1954 to 1959 and as a research metallurgist at the Sylvania Research Laboratory from 1959 to 1963 concentrating on multi-phase, multi-component solid-state diffusion theory. His education includes B.S. degrees in chemistry, physics and motion photography from the City College of New York in 1951 and an M.S. degree in metallurgical engineering from the Polytechnic Institute of Brooklyn in 1959.

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Dr. Hauge is in the silicon process physics group at the Thomas J. Watson Research Center, where he joined IBM in 1968. His research has included studies of the interaction of microwave and infrared radiation with semiconducting materials and the influence of carrier diffusion on the propagation of stable domains in the Gunn effect. His current work relates to the development of measurement techniques suitable for computer control. He received B.S., M.S. and Ph.D. degrees in electrical engineering in 1961, 1963 and 1967, respectively, from the University of Minnesota. Dr. Hauge is a member of the Institute of Electrical and Electronics Engineers.

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Dr. Schechtman is manager of photophysics and chemistry at the Research laboratory. He has been with IBM since 1968 and has been involved in theoretical and experimental studies of carrier generation and electronic transport in insulating molecular solids and laboratory automation of high-data-rate transient physics experiments. He has worked on VHF, UHF, and microwave circuit design for Bell Laboratories and Hughes Aircraft Company. He has also investigated tunneling in insulating films at the General Electric Research Laboratory and has studied optical and photoemission properties of organic solids at Stanford University. His degrees are in electrical engineering—B.E.E. from Cooper Union in 1963 and an M.S. and a Ph.D. in 1964 and 1969, respectively, from Stanford University. Dr. Schechtman is a member of the American Physical Society, Tau Beta Pi, Eta Kappa Nu, and Sigma Xi.

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Dr. So has been a member of the advanced technology materials science group since 1971 and has been involved in characterization of photomaterials. He joined IBM in 1965 at the Endicott development laboratory and was involved in analyses of diffusion techniques, electron microprobe analyzer, and holography methods. From 1967 to 1971 he was on education leave, doing graduate study at Pennsylvania State University. He received a B.S. degree from Duke University in 1962, an M.S. from Florida State University in 1964, and a Ph.D. from Pennsylvania State University in 1971, all in physics. He is a member of the American Physical Society, the Optical Society of America, and Sigma Xi.

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